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Moment inequalities for DVRL distributions, characterization and testing for exponentiality

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Abstract

Our goal in this paper is to establish inequalities for the moments of decreasing variance residual life (DVRL) distributions. As a consequence we derive a new characterization of exponentiality. Then we use two of these inequalities to construct new tests for exponentiality versus DVRL. Pitman's asymptotic relative efficiency is employed to assess the performance of the tests. For some classes of life distributions our tests are better than, or well comparable with, other available tests. We carried out numerical simulations and produced a table for the critical values of one of the proposed test.

Key words: Life distributions, Decreasing variance residual life, Moment inequalities, Characterization of exponentiality, Testing for exponentiality, Asymptotic efficiency.

1 Introduction

Suppose X is a nonnegative random variable which is interpreted as the lifetime of a device and has a distribution function $F = \{F(x), x \ge 0\}$, so its survival function is $\overline{F} = 1 - F$. We assume that all moments $\mathbf{E}[X^k], k = 1, 2, \ldots$ are finite and use the standard notations $\mu = \mathbf{E}[X]$ for the mean value and $\sigma^2 = \mathbf{Var}[X]$ for the variance of X. We need two characteristics, the conditional mean $\mu(x) = \mathbf{E}[X - x|X \ge x]$ and the conditional variance

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ACCEPTED MANUSCRIPT $\sigma^2(x) = \mathbf{Var}[X - x | X \ge x]$, usually called the mean residual life and the variance residual life.

We are interested in life distributions for which $\sigma^2(x), x \ge 0$ is decreasing and use the notation DVRL. Our goal is to derive inequalities for combined moments of random variables similar to X and use them in constructing tests for exponentiality versus the class DVRL. Among previous works in this direction we mention the papers by Hollander and Proschan (1975), Dallas (1981), Launer (1984), Gupta (1987), Ahmad (2001), Abu-Youssef (2002), Ahmad and Mugdadi (2004) and Chin and Min (2006).

In Section 2 we establish inequalities for the moments of lifetimes whose distributions are in the class DVRL. As a corollary we derive a new characterization of the exponential distribution. In Section 3 we use some of the inequalities to construct new tests for exponentiality versus the class DVRL. In Section 4, Pitman's asymptotic relative efficiency is used to assess the performance of the tests. The conclusion is that our tests are well comparable and in some cases even better than other tests widely used in statistical practice. In Section 5 we describe how to apply the test. We use real data set as an illustration of our results.

Moment inequalities and characterization of exponentiality $\mathbf{2}$

The main assumption is that the random variable $X \sim F$, with $F \in DVRL$, has finite moments. We express this as follows:

$$m_k := \mathbf{E}[X^k] = \int_0^\infty x^k \,\mathrm{d}F(x) < \infty \quad \text{for} \quad k = 1, 2, \dots$$

We are going to show that there are relations/inequalities involving the moments of X and combined moments of the random variables X_1 , X_2 and Y, where X_1 and X_2 are independent copies of X and

$$Y = \min\{X_1, X_2\}.$$

We can easily interpret Y as being the lifetime of a parallel system formed by two elements each with lifetime X.

Theorem 2.1 Under the above assumptions and notations, the following inequalities hold:

$$m_{1} m_{2} \leq 4 \mathbf{E} \left[X_{2} Y^{2} \right] - \frac{8}{3} \mathbf{E} \left[Y^{3} \right], \qquad (2.1)$$
$$m_{2}^{2} \leq \frac{16}{3} \mathbf{E} \left[X_{2} Y^{3} \right] - 4 \mathbf{E} \left[Y^{4} \right]. \qquad (2.2)$$

More generally, for any integer $k \geq 2$, we have:

$$\frac{k}{4} \mathbf{E} \left[X_1^2 X_2^2 Y^{k-1} \right] \le (k-1) \mathbf{E} \left[X_1 X_2^2 Y^k \right] - \frac{k(k-1)}{2(k+1)} \mathbf{E} \left[X_2^2 Y^{k+1} \right] - \frac{k(k-1)}{(k+1)} \mathbf{E} \left[X_1 X_2 Y^{k+1} \right] + \frac{4k(k-1)(k+1)+8}{(k+1)(k+2)} \mathbf{E} \left[X_2 Y^{k+2} \right] - \frac{8+k(k-1)(k+1)}{(k+1)(k+3)} \mathbf{E} \left[Y^{k+3} \right].$$
(2.3)

Proof. We prove the general inequality (2.3), assuming $k \ge 2$. Recall first that the functions $\mu(x)$ and $\sigma^2(x)$ can be expressed in terms of F, for all x > 0 such that F(x) < 1, as follows:

$$\mu(x) = \frac{1}{\bar{F}(x)} \int_x^\infty \bar{F}(u) \, \mathrm{d}u, \quad \sigma^2(x) = \frac{2}{\bar{F}(x)} \int_x^\infty \int_y^\infty \bar{F}(u) \, \mathrm{d}u \, \mathrm{d}y - \mu^2(x).$$

Clearly, $\mu(0) = \mu$ and $\sigma^2(0) = \sigma^2$.

Let us introduce two functions, v(x) and V(x), $x \ge 0$, where

$$v(x) = \int_{x}^{\infty} \overline{F}(z) dz$$
 and $V(x) = \int_{x}^{\infty} v(u) du$, $x \ge 0$.

We need now the well-known fact that $F \in \text{DVRL}$ if and only if the relation $\sigma^2(x) \leq \mu^2(x)$ holds for $x \geq 0$. It can be shown that this is equivalent to the following:

$$F \in \text{DVRL}$$
 if and only if $\overline{F}(x)V(x) \le v^2(x)$, for $x \ge 0$. (2.4)

We multiply both sides of the inequality in (2.4) by x^k , integrate with respect to x over the interval $(0, \infty)$ and introduce the notations I_1 and I_2 thus getting

$$I_1 := \int_0^\infty x^k \bar{F}(x) V(x) \, \mathrm{d}x \le \int_0^\infty x^k v^2(x) \, \mathrm{d}x := I_2.$$
(2.5)

ACCEPTED MANUSCRIPT Integrating I_1 by parts and using the fact that V'(x) = -v(x) gives this:

$$I_{1} = \int_{0}^{\infty} x^{k} \bar{F}(x) V(x) \, \mathrm{d}x = -x^{k} v(x) V(x) \Big|_{0}^{\infty} - \frac{1}{2} k x^{k-1} V^{2}(x) \Big|_{0}^{\infty} - I_{2} + \frac{1}{2} k(k-1) \int_{0}^{\infty} x^{k-2} V^{2}(x) \, \mathrm{d}x.$$
(2.6)

Now, the first two terms in the right-hand-side of (2.6) are equal to zero. What remains is combined with (2.5) thus getting

$$I_1 = -I_2 + \frac{1}{2} k(k-1) \int_0^\infty x^{k-2} V^2(x) \, \mathrm{d}x \le I_2.$$

This implies that

$$\int_{0}^{\infty} x^{k-2} V^{2}(x) \, \mathrm{d}x \le \frac{4 I_{2}}{k(k-1)}.$$
(2.7)

The next is to work out the integral in the left-hand-side of (2.7). We find

$$\int_{0}^{\infty} x^{k-2} V^{2}(x) \, \mathrm{d}x = \frac{1}{4} \mathbf{E} \left[\int_{0}^{\min\{X_{1}, X_{2}\}} x^{k-2} (X_{1} - x)^{2} (X_{2} - x)^{2} \, \mathrm{d}x \right]$$
$$= \frac{1}{4(k-1)} \mathbf{E} \left[X_{1}^{2} X_{2}^{2} Y^{k-1} \right] - \frac{1}{k} \mathbf{E} \left[X_{1} X_{2}^{2} Y^{k} \right]$$
$$+ \frac{1}{2(k+1)} \mathbf{E} \left[X_{2}^{2} Y^{k+1} \right] + \frac{1}{k+1} \mathbf{E} \left[X_{1} X_{2} Y^{k+1} \right]$$
$$- \frac{4}{k+2} \mathbf{E} \left[X_{2} Y^{k+2} \right] + \frac{1}{k+3} \mathbf{E} \left[Y^{k+3} \right].$$
(2.8)

Similarly, integrating I_2 by parts, one gets

$$I_{2} = \int_{0}^{\infty} x^{k} v^{2}(x) dx = \frac{2}{k+1} \int_{0}^{\infty} x^{k+1} v(x) \bar{F}(x) dx$$
$$= \frac{2}{k+1} \mathbf{E} \int_{0}^{\min\{X_{1}, X_{2}\}} x^{k+1} (X_{2} - x) dx$$
$$= \frac{2}{(k+1)(k+2)} \mathbf{E} \left[X_{2} Y^{k+2} \right]$$

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$$-\frac{2}{(k+1)(k+3)} \mathbf{E} \left[Y^{k+3} \right].$$
(2.9)

hence the required inequality (2.3) follows from relations (2.7) - (2.9).

Let us work a little more with the integrals I_1 and I_2 , see (2.5). Since $v(\infty) = 0$, $V(\infty) = 0$ and since all moments of X and of F are finite, we have that $\lim_{x\to\infty} x^k v(x) V(x) = 0$ for k = 0, 1, 2, ... We also have that $v(0) = \mu = m_1$, $V(0) = \frac{1}{2}m_2$. Notice that inequality (2.5) is true for any nonnegative k. We take k = 0 and then k = 1 and work either directly with (2.5), or use (2.6) whose right-hand-side becomes simple. This together with (2.9) can be summarized as follows:

If k = 0, then $I_1 = \frac{1}{2}m_1m_2 - I_2$, $I_2 = \mathbf{E}[X_2Y^2] - \frac{2}{3}\mathbf{E}[Y^3]$, hence we arrive at (2.1). If k = 1, then $I_1 = \frac{1}{2}V^2(0) - I_2 = \frac{1}{2} \cdot \frac{1}{4}m_2^2 - I_2$, $I_2 = \frac{1}{3}\mathbf{E}[X_2Y^3] - \frac{1}{4}\mathbf{E}[Y^4]$ and we arrive at (2.2).

This completes the proof of Theorem 2.1.

As a consequence, we derive a new characterization property of the exponential distribution.

Theorem 2.2 Suppose F is the distribution function of a nonnegative random variable X with finite moments m_k , k = 1, 2, ... and such that the conditional variance $\sigma^2(x) = \operatorname{Var}[X - x | X \ge x]$, $x \ge 0$ is a decreasing function. Let X_1 and X_2 be independent copies of X and $Y = \min\{X_1, X_2\}$. Then:

(a) F is exponential if and only if $m_1 m_2 = 4 \mathbf{E} [X_2 Y^2] - \frac{8}{3} \mathbf{E} [Y^3]$.

(b) F is exponential if and only if $m_2^2 = \frac{16}{3} \mathbf{E} [X_2 Y^3] - 4 \mathbf{E} [Y^4].$

Hint. For the 'if' part, let us assume that $X \sim Exp(\lambda)$. Then $Y \sim Exp(2\lambda)$, however we keep in mind that Y is not independent of X_1 and X_2 . We easily find m_1 , m_2 , $\mathbf{E}[Y^3]$, $\mathbf{E}[Y^4]$ and use conditioning arguments, or another way, to calculate $\mathbf{E}[X_2Y^2]$ and $\mathbf{E}[X_2Y^3]$. A substitution shows that the equalities in (a) and (b) hold true. For the 'only if' part, we start with the two equalities in (a) and (b) and follow the proof of the inequalities (2.1) and (2.2) thus arriving at relation (2.4). It remains only to mention that equality in (2.4) holds only if F is exponential, see e.g. Dallas (1981).

3 Application to hypothesis testing

3.1 Construction of tests versus DVRL

Suppose the lifetime X of a device has a distribution function F which is unknown. We have in our disposal a random sample X_1, X_2, \ldots, X_n of independent observations from F. We want to test the null hypothesis H_0 against its alternative H_1 , where

 H_0 : F is exponential, versus

 H_1 : F belongs to the class DVRL and F is not exponential.

We suggest to use the first two inequalities, (2.1) and (2.2), established in Theorem 2.1. For this purpose we introduce the following two quantities:

$$M^{(1)} = 4\mathbf{E} \left[X_2 Y^2 \right] - \frac{8}{3} \mathbf{E} \left[Y^3 \right] - m_1 m_2, \tag{3.1}$$

$$M^{(2)} = \frac{16}{3} \mathbf{E} \left[X_2 Y^3 \right] - 4 \mathbf{E} \left[Y^4 \right] - m_2^2.$$
(3.2)

According to Theorem 2.2, if F is exponential, this is hypothesis H_0 , we have $M^{(1)} = 0$ and $M^{(2)} = 0$. Hence, under hypothesis H_1 , in view of (2.1) and (2.2), we have $M^{(1)} > 0$ and $M^{(2)} > 0$. This motivates us to use the above quantities $M^{(1)}$ and $M^{(2)}$ as measures of departure of F from the exponential distribution.

We use the sample X_1, \ldots, X_n and define $Y_{ij} = \min\{X_i, X_j\}, i, j = 1, 2, \ldots, n$. Since we do not know F, and hence $M^{(1)}$ and $M^{(2)}$, we have to replace them by appropriate estimators, say $\hat{M}_n^{(1)}$ and $\hat{M}_n^{(2)}$, based on the sample X_1, \ldots, X_n . We take

$$\hat{M}_{n}^{(1)} = \frac{1}{n(n-1)} \sum_{i \neq j} \left\{ 4X_{j}Y_{ij}^{2} - \frac{8}{3}Y_{ij}^{3} - X_{i}X_{j}^{2} \right\},$$
(3.3)

$$\hat{M}_{n}^{(2)} = \frac{1}{n(n-1)} \sum_{i \neq j} \left\{ \frac{16}{3} X_{j} Y_{ij}^{3} - 4Y_{ij}^{4} - X_{i}^{2} X_{j}^{2} \right\}.$$
(3.4)

It is interesting to note the difference between the pair $M^{(1)}$, $\hat{M}_n^{(1)}$ and the pair $M^{(2)}$, $\hat{M}_n^{(2)}$. Clearly, $M^{(1)}$ involves combined moments of total order equal to 3, while the total order of combined moments in $M^{(2)}$ is equal to 4. The estimators $\hat{M}_n^{(1)}$ and $\hat{M}_n^{(2)}$ involve empirical moments of total order equal to 3

ACCEPTED MANUSCRIPT and 4, respectively. It can be shown that $\hat{M}_n^{(1)} \xrightarrow{P} M^{(1)}$ and $\hat{M}_n^{(2)} \xrightarrow{P} M^{(2)}$ as $n \to \infty$, where \xrightarrow{P} stands for convergence in probability.

Let us propose now the test statistics. If the mean value μ of F is known to us, we use $\hat{M}_n^{(1)}/\mu^3$ and $\hat{M}_n^{(2)}/\mu^4$ as scale-invariant test statistics. If μ is unknown, we replace it by the sample mean \bar{X} and in this case the scale-invariant test statistics are denoted by $\hat{T}_n^{(1)}$ and $\hat{T}_n^{(2)}$ and defined by

$$T_n^{(1)} = \hat{M}_n^{(1)} / \bar{X}^3$$
 and $T_n^{(2)} = \hat{M}_n^{(2)} / \bar{X}^4$.

(3.5)

Asymptotic properties 3.2

We follow the general approach of using U-statistics. For any two variables, X_i and X_j , from the sample X_1, X_2, \ldots, X_n of independent observations, we define the functions

$$\phi^{(1)}(X_1, X_2) = 4X_2Y^2 - \frac{8}{3}Y^3 - X_1X_2^2, \qquad (3.6)$$

$$\phi^{(2)}(X_1, X_2) = \frac{16}{3} X_2 Y^3 - 4Y^4 - X_1^2 X_2^2.$$
(3.7)

The functions $\phi^{(1)}(X_1, X_2)$ and $\phi^{(2)}(X_1, X_2)$ are not symmetric and we we need their symmetrization. We take

$$\bar{\phi}^{(1)}(X_1, X_2) = \frac{1}{2} \left\{ \phi^{(1)}(X_1, X_2) + \phi^{(1)}(X_2, X_1) \right\}$$

and similarly we define $\bar{\phi}^{(2)}(X_1, X_2)$ in terms of $\phi^{(2)}(X_1, X_2)$. Then the test statistics $\hat{M}_n^{(1)}$ and $\hat{M}_n^{(2)}$ are equivalent to U-statistics $U_n^{(1)}$ and $U_n^{(2)}$ of order 2, where

$$U_n^{(1)} = \frac{1}{\binom{n}{2}} \sum_{i < j}^n \bar{\phi}^{(1)}(X_i, X_j), \quad U_n^{(2)} = \frac{1}{\binom{n}{2}} \sum_{i < j}^n \bar{\phi}^{(2)}(X_i, X_j).$$
(3.8)

Based on classical results of Hoeffding's type, see Serfling (1980), Randles (1982) or Severini (2005), the following two theorems summarize the asymptotic properties of $T_n^{(1)}$ and $T_n^{(2)}$ as defined by (3.5). We use also the notations $T^{(1)} = M^{(1)}/\mu^3$ and $T^{(2)} = M^{(2)}/\mu^4$.

Theorem 3.1 If $n \to \infty$, then $\sqrt{n}(T_n^{(1)} - T^{(1)})$ is asymptotically normal with mean 0 and variance B_1^2 , where

ACCEPTED MANUSCRIPT $B_{1}^{2} = \frac{1}{\mu^{6}} \operatorname{Var} \left\{ 4 \int_{0}^{X_{1}} \int_{y}^{\infty} yu \, \mathrm{d}F(u) \, \mathrm{d}y - \frac{2}{3} X_{1}^{3} \bar{F}(X_{1}) + 4 X_{1} \int_{0}^{X_{1}} u^{2} \, \mathrm{d}F(u) - \frac{16}{3} \int_{0}^{X_{1}} u^{3} \, \mathrm{d}F(u) - X_{1}^{2} m_{1} - X_{1} m_{2} \right\}.$ (3.9)

Theorem 3.2 If $n \to \infty$, then $\sqrt{n}(T_n^{(2)} - T^{(2)})$ is asymptotically normal with mean 0 and variance B_2^2 , where

$$B_{2}^{2} = \frac{1}{\mu^{8}} \operatorname{Var} \left\{ 8 \int_{0}^{X_{1}} \int_{y}^{\infty} y^{2} u \, \mathrm{d}F(u) \, \mathrm{d}y - \frac{4}{3} X_{1}^{4} \bar{F}(X_{1}) + \frac{8}{3} X_{1} \int_{0}^{X_{1}} u^{3} \, \mathrm{d}F(u) - 4 \int_{0}^{X_{1}} u^{4} \, \mathrm{d}F(u) - X_{1}^{2} \, m_{2} \right\}.$$

$$(3.10)$$

Proof. The proof of Theorem 3.1 and Theorem 3.2 is based on the same idea. First, as $n \to \infty$, we have $\bar{X} \xrightarrow{P} \mu$, $\hat{M}_n^{(1)} \xrightarrow{P} M^{(1)}$, $\hat{M}_n^{(2)} \xrightarrow{P} M^{(2)}$ and we derive that also $T_n^{(1)} \xrightarrow{P} T^{(1)}$, $T_n^{(2)} \xrightarrow{P} T^{(2)}$. We use now results from Serfling (1980) and Randles (1982) to conclude that, as $n \to \infty$, $T_n^{(1)}$ and $\hat{M}_n^{(1)}/\mu^3$, have asymptotically the same normal distribution $N(0, B_1^2)$, and similarly $T_n^{(2)}$ and $\hat{M}_n^{(2)}/\mu^4$, have asymptotically the same normal distribution $N(0, B_2^2)$. The variance B_i^2 , i = 1, 2, has the following explicit form: $B_i^2 = m^2 \operatorname{Var}[\psi^{(i)}(X_1)]$, where m = 2, is the order of the U-statistics, see (3.8), and

$$\psi^{(i)}(X_1) = \frac{1}{2} \Big\{ \mathbf{E}[\phi^{(i)}(X_1, X_2) | X_1] + \mathbf{E}[\phi^{(i)}(X_2, X_1) | X_1] \Big\}, \ i = 1, 2.$$
(3.11)

The next step is to use (3.11) and the functions $\phi^{(i)}(X_1, X_2)$ defined by (3.6) and (3.7). After some transformations we find that

$$\psi^{(1)}(X_1) = \frac{1}{2} \left\{ 8 \int_0^{X_1} \int_y^{\infty} y u \, \mathrm{d}F(u) \, \mathrm{d}y - \frac{4}{3} X_1^3 \,\bar{F}(X_1) + 4 \, X_1 \int_0^{X_1} u^2 \, \mathrm{d}F(u) - \frac{16}{3} \int_0^{X_1} u^3 \, \mathrm{d}F(u) - X_2 \, m_1 - X_1 \, m_2 \right\},$$
(3.12)
$$\psi^{(2)}(X_1) = \frac{1}{2} \left\{ 16 \int_0^{X_1} \int_y^{\infty} y^2 u \, \mathrm{d}F(u) \, \mathrm{d}y - \frac{8}{3} \, X_1^4 \bar{F}(X_1) + \frac{16}{3} \, X_1 \int_0^{X_1} u^3 \, \mathrm{d}F(u) \right\}$$

$$-8 \int_{0}^{X_{1}} u^{4} dF(u) - 2 X_{1}^{2} m_{2} \bigg\}.$$
(3.13)

Finally, taking the variance of (3.12), we arrive at the value B_1^2 as given in (3.9). Similarly, B_2^2 , given in (3.10) is obtained by taking the variance of (3.13).

Corollary If the null hypothesis H_0 is true, e.g., the life distribution F is exponential with parameter 1, then, as $n \to \infty$, the limiting distribution of $\sqrt{n}(T_n^{(i)} - T^{(i)})$, i = 1, 2, is normal, $N(0, \sigma_i^2)$, with null-variances $\sigma_1^2 = 4/3$ and $\sigma_2^2 = 56/27$.

Hint. Using the explicit expressions for the exponential distribution function and its density, and after a series of calculations (we do not include here the technical details), we find that $\sigma_1^2 = 4/3$ and $\sigma_2^2 = 56/27$.

4 Pitman's asymptotic efficiency

To compare the goodness of the test statistics $T_n^{(i)}$, i = 1, 2, we use the concept of Pitman's asymptotic efficiency (PAE); see e.g. Nikitin (1995). Here are some details. Let $F(x; \theta_n)$ be a sequence of alternative distribution functions, where x > 0, $\theta_n = \theta_0 + c/\sqrt{n}$ and c is a fixed nonnegative number. If c = 0, then θ_0 will correspond to the exponential distribution. We assume that F has a density function, f, and further, that f is smooth.

If T is a test statistic, its PAE is given by

$$PAE(T, F(\theta_0)) = \frac{1}{\sigma_0} \lim_{n \to \infty} \left\{ \frac{\mathrm{d}}{\mathrm{d}\theta} \mathbf{E}[T_n] \right\},$$
(4.1)

where σ_0^2 is the asymptotic variance corresponding to the null hypothesis.

Hence for our tests $\hat{M}_n^{(1)}$ and $\hat{M}_n^{(2)}$, see (3.3) and (3.4), we take $n \to \infty$, in which case $\theta \to \theta_0$, thus finding the following expressions:

$$\lim_{\theta \to \theta_0} \frac{\mathrm{d}\{\hat{M}_n^{(1)}(\theta)\}}{\mathrm{d}\theta} = 8 \int_0^\infty \int_x^\infty x u \{\bar{F}'(x,\theta_0)f(u,\theta_0) + \bar{F}(x,\theta_0)f'(u,\theta_0)\} \mathrm{d}u \,\mathrm{d}x$$
$$-16 \int_0^\infty x^2 \bar{F}(x,\theta_0)\bar{F}'(x,\theta_0) \,\mathrm{d}x - 2 \int_0^\infty \bar{F}'(x,\theta_0) \,\mathrm{d}x$$
$$-2 \int_0^\infty x \bar{F}'(x,\theta_0) \,\mathrm{d}x, \qquad (4.2)$$

$$\lim_{\theta \to \theta_0} \frac{\mathrm{d}\{\hat{M}_n^{(2)}(\theta)\}}{\mathrm{d}\theta} = 16 \int_0^\infty \int_x^\infty x^2 u \Big\{ \bar{F}'(x,\theta_0) f(u,\theta_0) + \bar{F}(x,\theta_0) f'(u,\theta_0) \Big\} \mathrm{d}u \,\mathrm{d}x \\ -32 \int_0^\infty x^3 \bar{F}(x,\theta_0) \bar{F}'(x,\theta_0) \,\mathrm{d}x - 8 \int_0^\infty x \bar{F}'(x,\theta_0) \,\mathrm{d}x.$$
(4.3)

Pitman's asymptotic relative efficiency is usually calculated for certain specific tests and specific families of life distributions. As an illustration we have chosen three distributions widely used in reliability analysis and calculated their PAE's. The distributions of interest are:

- (a) Linear failure rate distribution F_1 : $\overline{F}_1(x;\theta) = e^{-x-(\theta/2)x^2}$, x > 0, $\theta > 0$. (b) Weibull distribution F_2 : $\overline{F}_2(x;\theta) = e^{-x^{\theta}}$, x > 0, $\theta > 1$. (c) Makeham distribution F_3 : $\overline{F}_3(x;\theta) = e^{-x-\theta(x+e^{-x})}$, x > 0, $\theta > 0$.

It is worth mentioning that the Weibull distribution with parameter $\theta > 1$ has a decreasing VRL, and this property holds also for the two others.

The quality of the tests $T_n^{(1)}, T_n^{(2)}$ is best seen when comparing them with other available tests. A well-known and widely used test has been described by Hollander and Proschan (1975). These authors proposed a test, V^* , for exponentiality versus DMRL (decreasing **mean** residual life). Recently, Abu-Youssef (2002) proposed a test Δ_n for DMRL based on a moment inequality. The results of our calculations of the Pitman asymptotic efficiency, together with the calculations of Hollander and Proschan (1975) and Abu-Youssef (2002) are summarized in Table 1.

These calculations clearly indicate that the tests proposed in this paper are well comparable with other tests widely used in statistical practice. In some cases, e.g. for life distributions with linear failure rate, the test $T_n^{(2)}$ is better than other tests.

Table 1

Distribution	V^*	$\hat{\Delta}_n$	$T_n^{(1)}$	$T_n^{(2)}$
Linear failure rate, F_1	0.906	0.919	0.866	1.389
Weibull, F_2	0.846	0.710	0.532	0.638
Makeham, F_3	0.242	0.201	0.143	0.153

Pitman's asymptotic efficiency (PAE) of V^* , $\hat{\Delta}_n$, $T_n^{(1)}$ and $T_n^{(2)}$

Remark. Comparing the two tests $T_n^{(1)}$ and $T_n^{(2)}$ we see that $T_n^{(2)}$ is better. This can be explained by the fact that they both involve combined moments of X_1, X_2 and Y, however for $T_n^{(2)}$ the total order of moments is 4, while for $T_n^{(1)}$ the order is 3. This observations suggests to look for tests based on combined

moments of a higher total order with the expectation to get a better efficiency. We conjecture that this can be achieved by using the inequality (2.3) for k = 2, 3 or more. The test statistics $T_n^{(k)}$ will be of the form $T_n^{(k)} = \hat{M}_n^{(k)}/\bar{X}^{k+2}$, where

$$\begin{split} \hat{M}_{n}^{(k)} &= \frac{1}{n(n-1)} \sum_{i \neq j} \sum \left[X_{i} X_{j}^{2} Y_{ij}^{k} - \frac{k}{2(k+1)} X_{j}^{2} Y_{ij}^{k+1} - \frac{k}{k+1} X_{i} X_{j} Y_{ij}^{k+1} \right. \\ &+ \frac{4k(k+1) + 8}{(k+1)(k+2)} X_{j} Y_{ij}^{k+2} - \frac{8 + k(k+1)}{(k+1)(k+3)} Y_{ij}^{k+3} - \frac{k X_{1}^{2} X_{2}^{2} Y_{ij}^{k-1}}{4(k-1)} \right]. \end{split}$$

5 Applying the test

To carry out the test, we use the available sample X_1, \ldots, X_n and calculate, for i = 1 and i = 2, the value $t_n = \sqrt{n} T_n^{(i)}/\sigma_i$, where σ_i^2 is the variance of the distribution corresponding to the null hypothesis. Now given α , a significance level, we compare t_n and the normal variate value $z_{1-\alpha}$. If t_n exceeds $z_{1-\alpha}$, then we reject the hypothesis H_0 . Otherwise, we accept the null hypothesis H_0 .

Comparing $T_n^{(1)}$ and $T_n^{(2)}$, we may suggest that the test $T_n^{(2)}$ is better. To numerically illustrate the test $T_n^{(2)}$, we have simulated the lower and the upper percentile points for the significance level $\alpha = 0.01$, 0.05 and 0.10. The calculation of the test $T_n^{(2)}$ is based on 5,000 simulated samples from the standard exponential distribution. Table 2 shows the critical values for the test statistic $T_n^{(2)}$.

As an illustration, we have estimated the power of $T_n^{(2)}$ when alternatives are the Linear failure rate and the Weibull distributions. Our findings are summarized in Table 3.

Finally, as an illustration, we consider a real data set representing 40 patients suffering from blood cancer. We use the data as given in Hindi and Abouammoh (2001). The ordered life times (in days) are provided in Table 4. Based on this data set, the value of the test statistic $T_n^{(2)}$ is equal to 0.3168. This value is greater than the critical value in Table (2) at 90% upper percentile, hence, we reject the null hypothesis H_0 in favor of the alternative H_1 . This means that the data set comes from DVRL distribution. This is agreeing with the conclusion of Hendi and Abouammoh (2001).

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A variation of this work is a part of the doctoral dissertation of the first named

n	0.01	0.05	.0.10	0.90	0.95	0.99
10	-1.4908	-0.8347	-0.5621	0.3653	0.4471	0.6366
15	-1.4868	-0.8082	-0.5085	0.3578	0.4236	0.5758
25	-1.4791	-0.7950	-0.4761	0.3382	0.3957	0.5188
30	-1.4241	-0.6750	-0.4190	0.3331	0.3878	0.5106
35	-1.3629	-0.6738	-0.4271	0.3224	0.3701	0.4739
40	-1.3617	-0.6627	-0.4102	0.3122	0.3670	0.4594
45	-1.3020	-0.6392	-0.3929	0.3032	0.3523	0.4467
50	-1.2127	-0.6026	-0.3692	0.2924	0.3412	0.4223
60	-1.1737	-0.5789	-0.3737	0.2854	0.3266	0.4088
70	-1.1349	-0.5645	-0.3481	0.2697	0.3206	0.4040
80	-1.1220	-0.5271	-0.3275	0.2596	0.3018	0.3786
90	-0.9280	-0.5000	-0.3130	0.2511	0.2934	0.3709
100	-0.8508	-0.4552	-0.2989	0.2389	0.2704	0.3527

Table 2 Critical values for the test statistic $T_n^{(2)}$

Table 3 Power estimates for the test statistic $T_n^{(2)}$

Distribution	Parameter	Sample size n			
	θ	20	30	40	
F_1	1	0.973	0.977	0.975	
Linear failure rate	2	0.994	0.998	1.000	
	3	1.000	1.000	1.000	
F_2	1	0.944	0.945	0.950	
Weibull	2	0.999	1.000	1.000	
	3	1.000	1.000	1.000	

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115	181	255	418	441	461	516	739	743	789	807	865
924	983	1024	1062	1063	1165	1191	1222	1222	1251	1277	1290
1357	1369	1408	1455	1478	1549	1578	1578	1599	1603	1605	1696
1735	1799	1815	1852								

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Table 4

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Sample Size